

Notice of References Cited

Application/Control No.

09/866,533

Applicant(s)/Patent Under
Reexamination
MIRKIN ET AL.

Examiner

William P. Fletcher III

Art Unit

1762

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,539,089 A	09-1985	Binnig et al.	204/192.12
	B	US-5,227,626 A	07-1993	Okada et al.	250/234
	C	US-5,935,454 A	08-1999	Tada et al.	216/41
	D	US-6,403,382 B1	06-2002	Zhu et al.	436/176
	E	US-6,635,311 B1	10-2003	Mirkin et al.	427/256
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	N	JP-10-267824-A	10-1998	Japan	Tamada et al.	G01N 13/00
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NON-PATENT DOCUMENTS

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	U	Encyclopedia of Materials Characterization: Surfaces, Interfaces, Thin Films; © 1992 by Butterworth-Heinemann, a division of Reed Publishing (USA) Inc., page 703.
	V	Definitions of "mica," "chemisorption," and "hydrophilic" from Hawley's Condensed Chemical Dictionary, 12th Edition, © 1993 by Van Nostrand Reinhold, pages 783-784, 254, and 618, respectively.
	W	Jaschke et al., Deposition of Organic Material by the Tip of a Scanning Force Microscope, Langmuir 1995, 11, 1061-1064.
	X	Mirkin et al., Effect of Water on Lateral Force Microscopy in Air, Langmuir 1997, 13, 6864-6868.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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